FCC 15.247 & RSS-247 2.4GHz Test Report

for

LG Electronics Inc.

222, LG-ro, Jinwi-myeon Pyeongtaek-Si, Gyeonggi-Do, 17709 Republic of Korea

Product Name : Notebook Computer

Model Name : (1)16ZB90Q (2)16ZG90Q

Brand LG

FCC ID : BEJNT-16ZB90Q

IC : 2703H-16ZB90Q

Prepared by: : AUDIX Technology Corporation,

EMC Department





The test report is based on a single evaluation of one sample of the above-mentioned products. It does not imply an assessment of the whole production and does not permit the use of the test lab logo.



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APPENDIX A TEST DATA AND PLOTS APPENDIX B TESTPHOTOGRAPHS





TEST REPORT

Applicant : LG Electronics Inc.

Manufacturer : LG Electronics Inc.

Factory : LG Electronics Nanjing New Technology Co., Ltd.

EUT Description

(1) Product : Notebook Computer

(2) Model : (1)16ZB90Q (2)16ZG90Q

(3) Brand : LG

(4) Power Supply: DC 20V, 3.25A

Applicable Standards:

Title 47 CFR FCC Part 15 Subpart C RSS-Gen (Issue 5), Amendment 2, February 2021 RSS-247 (Issue 2), February 2017

Audix Technology Corp. tested the equipment mentioned in accordance with the requirements set forth in the above standards. Test results indicate that the equipment tested is capable of demonstrating compliance with the requirements as documented within this report.

Audix Technology Corp. does not assume responsibility for any conclusions and generalizations drawn from the test results with regard to other specimens and samples.

Date of Report: 2022. 07. 20

Reviewed by: Sabrina Wang/Administrator)

Approved by: Johnny Hsueh/Section Manager)



1. REVISION RECORD OF TEST REPORT

Edition No	Issued Date	Revision Summary	Report Number
0	2022. 07. 20	Original Report	EM-F220478

2. SUMMARY OF TEST RESULTS

Rule	Description	Results			
15.207	Conducted Emission	PASS			
15.247(d)/15.205	Radiated Band Edge and Radiated Spurious Emission	PASS			
15.247(a)(1)	20dB/Occupied Bandwidth	PASS			
15.247(a)(1)	Carrier Frequency Separation	PASS			
15.247(a)(1)(iii)	Time of Occupancy	PASS			
15.247(a)(1)(iii)	Number of Hopping Channels	PASS			
15.247(b)(1)	Maximum Peak Output Power	PASS			
Conducted Band Edges and Conducted Spurious Emission Conducted Spurious Emission					
15.203 Antenna Requirement Complia					
Note: The uncertainties value is not used in determining the result.					

3. GENERAL INFORMATION

3.1. Description of Application

A muli 2 au 4	LG Electronics Inc.
Applicant	222, LG-ro, Jinwi-myeon Pyeongtaek-Si, Gyeonggi-Do, 17709 Republic of Korea
Manufacturer	LG Electronics Inc.
Manuracturer	222, LG-ro, Jinwi-myeon Pyeongtaek-Si, Gyeonggi-Do, 17709 Republic of Korea
Footomy	LG Electronics Nanjing New Technology Co., Ltd.
Factory	No.346, Yaoxin Road, Economic & Technical Development Zone, Nanjing, China.
Product	Notebook Computer
Brand	LG
Madal	(1)16ZB90Q (2)16ZG90Q
Model	The difference between all models is different in the sales customers.





3.2. Description of EUT

Test Model	16ZB90Q							
Serial Number	N/A							
Power Rating	DC 20V, 3.25A							
Software Version	XY (X, Y can be 0 to 9 for different SW version not in	XY (X, Y can be 0 to 9 for different SW version not influence RF parameter)						
RF Features	WLAN:802.11 a/b/g/n/ac/ax Bluetooth: BT and BLE (BT 5.1)							
	2.4 GHz							
	802.11b	1T1R						
	802.11g	1T1R						
	802.11n-HT20	2T2R						
	802.11n-HT40	2T2R						
	802.11ax-HE20	2T2R						
	802.11ax-HE40	2T2R						
Transmit Type	BT/BLE	1T1R						
	U-NII Bands							
	802.11a	1T1R						
	802.11n-HT20/802.11ac-VHT20/802.11ax-HE20	2T2R						
	802.11n-HT40/802.11ac-VHT40/802.11ax-HE40	2T2R						
	802.11ac-VHT80/802.11ax-HE80	2T2R						
	802.11ac-VHT160/802.11ax-HE160	2T2R						
	The MIMO is uncorrelated and supported SDM mode only.							
	Sample No. Test Item	Firmware						
Test Sample	03 AC Conduction, RSE, RF Conducted	N/A						
Sample Status	Trial sample							
Date of Receipt	2022. 07. 01							
Date of Test	2022. 07. 01 ~ 13							
Interface Ports of EUT	 One HDMI Port Two USB Type C Ports One Earphone Port One Micro SD Card Slot Two USB 3.0 Ports 							
Accessories Supplied	AC AdapterLAN Gender							

3.3. Reference Test Guidance

ANSI C63.10:2013

3.4. Antenna Information

	Antenna Part	Manufacturer	Antenna Type	Frequency		Gain (dBi)		
No.					Max		Directional	
	Number			(MHz)	Main	AUX	Directional	
				2400	3.10	1.90	2.54	
				2425	4.80	2.30	3.73	
				2450	4.40	2.20	3.44	
	WA-P-LELE-04-026	INPAQ		2475	4.50	3.20	3.90	
			PAQ Mono-Pole	2500	5.30	3.40	4.45	
				5150	2.70	2.70	2.70	
1.				5250	3.70	3.70	3.70	
				5350	3.10	3.10	3.10	
				5725	3.10	3.10	3.10	
				5825	3.00	3.00	3.00	
				5925	2.00	2.30	2.15	
				6525	1.90	2.20	2.05	
				7125	1.90	2.10	2.00	

According to KDB 662911 D01 d) ii), transmit signals are completely uncorrelated, then Directional gain = $10 \log[(10^{G1/10} + 10^{G2/10} + ... + 10^{GN/10})/N_{ANT}]$ dBi We chose the antenna gain corresponding to the frequency listed on the table which is closer to center frequency of WLAN.





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3.5. EUT Specifications Assessed in Current Report

Mode	Fundamental Range (MHz)	Channel Number	Modulation	Data Rate (Mbps)
Bluetooth	2402-2480	79	FHSS (GFSK, π /4 DQPSK, 8-DPSK)	1/2/3

	Channel List								
Channel	Frequency	Channel	Frequency	Channel	Frequency	Channel	Frequency		
Number	(MHz)	Number	(MHz)	Number	(MHz)	Number	(MHz)		
00	2402	20	2422	40	2442	60	2462		
01	2403	21	2423	41	2443	61	2463		
02	2404	22	2424	42	2444	62	2464		
03	2405	23	2425	43	2445	63	2465		
04	2406	24	2426	44	2446	64	2466		
05	2407	25	2427	45	2447	65	2467		
06	2408	26	2428	46	2448	66	2468		
07	2409	27	2429	47	2449	67	2469		
08	2410	28	2430	48	2450	68	2470		
09	2411	29	2431	49	2451	69	2471		
10	2412	30	2432	50	2452	70	2472		
11	2413	31	2433	51	2453	71	2473		
12	2414	32	2434	52	2454	72	2474		
13	2415	33	2435	53	2455	73	2475		
14	2416	34	2436	54	2456	74	2476		
15	2417	35	2437	55	2457	75	2477		
16	2418	36	2438	56	2458	76	2478		
17	2419	37	2439	57	2459	77	2479		
18	2420	38	2440	58	2460	78	2480		
19	2421	39	2441	59	2461		•		

3.6. Description of Key Components

3.6.1. For the All Component Lists

Item	Supplier	Model / Type	Character
	T. P.	Win 10	
System	Microsoft	Win 10 Pro	
		Win11	
Main Board	LG	Queen LP4X MAIN B/D PCB	Manufacturer: #1 HannstarBoardTech(Jiang Yin)Corp.,Ltd. #2 Elec&Eltek Company (MCO) Limited.
WLAN SUB Board	LG	16Z90Q B2B SUB B/D	Manufacturer: #1 HannstarBoardTech(Jiang Yin)Corp.,Ltd. #2 Elec&Eltek Company (MCO) Limited. #3 JiangSuHuaShen Electronic co.,ltd (HXF)
	Intel	i7-1260P	2.5GHz
	Intel	i7-1255U	2.5GHz
CPU	Intel	i5-1240P	2.1GHz
(Socket: BGA1744)	Intel	i5-1235U	2.1GHz
,	Intel	i3-1220P	1.5GHz
	Intel	i3-1215U	1.5GHz
16" LCD Panel	LG Display	LP160WQ1 (SP)(B2)	Resolution: 2560 x 1600, 60Hz WQXGA IPS
	SK hynix		1TB
			512GB
a (995)			256GB
Storage (SSD)			1TB
	Samsung		512GB
			256GB
			32GB LPDDR4x(On Board)
	Samsung		16GB LPDDR4x(On Board)
M (DA) ()			8GB LPDDR4x(On Board)
Memory (RAM)			32GB LPDDR4x(On Board)
	SK Hynix		16GB LPDDR4x(On Board)
			8GB LPDDR4x(On Board)
Battery Pack	LG	LBV7227E	DC7.74V, 80Wh Typ 10336mAh
WLAN Combo Card	Intel	AX211D2W	WLAN and BT, 2x2 PCle M.2 1216 SD adapter card FCC ID: PD9AX211D2 IC: 1000M-AX211D2
WLAN Combo Antenna	LG (INPAQ)	WA-P-LELE-04-026	PCB, Mono-pole Type Main: Black, Aux: Gray
17 1 1	TIC	KT0120B8	
Keyboard	LITE ON	SN8101	
	LITE-ON	SP8001(SG-A0630-00A)	
Touch Pad	ELAN	SD081A-36H0	
W. I. G	Chicony	CKFKH33-0	EBP63421711
Web Camera	Luxvisions	0BF108N3	EBP63421709



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Item	Supplier	Model / Type	Character		
	SUZHOU MEC	80-5946-111	(White) 10/100 Megabit Ethernet		
	ELECTRONICS	80-5946-101	(Black) 10/100 Megabit Ethernet		
	ADIN TECH CO. I TO	GD-08MF-36-WH-LP10	(White) 10/100 Megabit Ethernet		
LAN Gender (Type C to LAN)	ARIN TECH CO. LTD	GD-08MF-36-BK-LP11	(Black) 10/100 Megabit Ethernet		
(Type C to LAIV)	HUIZHOU DEHONG	370-50713	(White) 10/100 Megabit Ethernet		
	TECHNOLOGY CO.,LTD.	370-50714	(Black) 10/100 Megabit Ethernet		
	Type C to LAN: Shielded, Undetached, 0.12m				
	LG (HONOR) ADT-65DSU-D03-2		I/P: AC 100-240V, 1.6A, 50-60Hz O/P: DC 20V, 3.25A		
AC Adapter (65W)	DC Power Cord: Non-Shielded, Undetached, 1.5m				
	AC Power Cord: Non-Shielded, Detached, 1.0m (2C) (For Other Countries)				
	AC Power Cord: Non-Shielded, Detached, 1.55m (2C) (For US, Canada, Mexico)				

Remark: For more detailed features description, please refer to the manufacturer's specifications or the user manual.

3.6.2. The EUT collocates with following worst components, which are used to establish a basic configuration of system during test:

	_		
SKU (Mode) 1			
Main Board		Queen LP4X MAIN B/D PCB	
SUB Board		LG, 16Z90Q B2B SUB B/D	
CPU		Intel, i7-1260P	
16" LCD Panel		LG Display, LP160WQ1(SP)(B2)	
Stores (SSD)		Samsung, 1TB	
Storage (SSD)		Samsung, 256GB	
Memory (RAM		32GB	
Battery Pack		LG, LBV7227E (80Wh)	
Keyboard		TIC, KT0120B8	
Touch Pad		LITE-ON, SP8001(SG-A0630-00A)	
Web Camera		Chicony, CKFKH33-0	
WLAN Combo	Card	Intel, AX211D2W	
WLAN Combo Antenna		LG (INPAQ), WA-P-LELE-04-026	
HDMI		2560 x 1600, 60Hz	
Type C #1	AC Adapter	LG (HONOR), ADT-65DSU-D03-2	
Type C #2	Link to LAN Gender	MEC (Black) (100Mbps)	



3.7. Test Configuration

Mode	Duty Cycle (x)	T (ms)	Duty Cycle Correction Factor (dB)
BT	N/A	2.890	N/A

	AC Conduction	
Normal operation		

	Modulation	Data Rate	Test Channel	
Radiated Test Case	Radiated Spurious Emission (30MHz~1GHz)	GFSK	1Mbps	78

	Modulation	Data Rate	Test Channel	
	Radiated Band Edge Note 1 & 2	GFSK	1Mbps	00/78
Radiated Test Case	Radiated Balld Edge	8-DPSK	3Mbps	00/78
	Radiated Spurious Emission Note1	GFSK	1Mbps	00/39/78
	20dD/Occumied Dendwidth	GFSK	1Mbps	00/39/78
	20dB/Occupied Bandwidth	8-DPSK	3Mbps	00/39/78
	Commiss Empayson as Comparation	GFSK	1Mbps	00/39/78
	Carrier Frequency Separation	8-DPSK	3Mbps	00/39/78
	Time of Occurrence	GFSK	1Mbps	00/39/78
	Time of Occupancy	8-DPSK	3Mbps	00/39/78
Conducted Test Case	N 1 CH : Cl 1	GFSK	1Mbps	39
Conducted Test Case	Number of Hopping Channels	8-DPSK	3Mbps	39
	Maximum Paak Output Power	GFSK	1Mbps	00/39/78
	Maximum Peak Output Power	8-DPSK	3Mbps	00/39/78
	Dand Edges	GFSK	1Mbps	00/78
	Band Edges	8-DPSK	3Mbps	00/78
	Spurious Emission	GFSK	1Mbps	00/39/78
	Spurious Emission	8-DPSK	3Mbps	00/39/78

Note 1 : Mobile Device,	and 3 axis were assessed	. The worst scenar	rio for Radiated Sp	urious Emission	as follow:
☐Lie ☐Side ☐S	Stand				

Portable Device, and 3 axis were assessed. The worst scenario for Radiated Spurious Emission as follow:

■Lie □Side □Stand

Note 2: We performed testing of the highest and lowest data rate.



3.8. Output Power Setting

Contro Enggueray (MIIa)	Power Setting		
Centre Frequency (MHz)	GFSK	8-DPSK	
2402	12	7	
2441	12	7	
2480	12	7	

3.9. Tested Supporting System List

3.9.1. Support Peripheral Unit

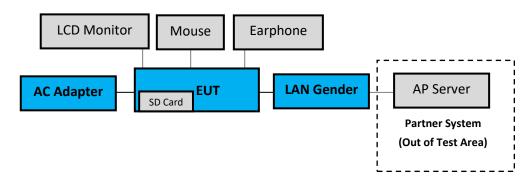
No.	Product	Brand	Model No.	Serial No.	Approval
1.	LCD Monitor	LG	22LK330-DB	N/A	N/A
2.	USB Mouse	Logitech	M-B0001	N/A	N/A
3.	Earphone	APPLE	N/A	N/A	N/A
4.	SD Card	ADATA	MicroSDHC Card	N/A	N/A
Partne	er System				
					FCC ID:
5.	AP Server	ASUS	RT-AX88U	N/A	MSQ-RTAXHP00
					IC: 3568A-RTAXHP00

3.9.2. Cable Lists

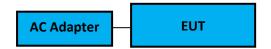
No.	Cable Description Of The Above Support Units		
1	HDMI Cable: Shielded, Detachable, 1.0m		
1.	AC Power Cord: Unshielded, Detachable, 1.8m		
2.	USB Cable: Unshielded, Undetachable, 1.8m		
3.	Earphone Cable: Unshielded, Undetachable, 1.2m		
4.	N/A		
5	AC adapter: M/N:WA-30B12, Cable: Unshielded, Detachable, 1.2m		
5.	LAN cable: Unshielded, Detachable, 3.0m		
6.	LAN cable: Unshielded, Detachable, 1.8m		

3.10.Setup Configuration

3.10.1. EUT Configuration for Power Line & Radiated Emission



3.10.2. EUT Configuration for RF Conducted Test Items



3.11. Operating Condition of EUT

Test program "DRTU" is used for enabling EUT BT function under continues transmitting and choosing data rate/ channel.

[ANT AUX port (A Button in DRTU), ANT Main port (B Button in DRTU)].

3.12.Description of Test Facility

Name of Test Firm	Audix Technology Corporation / EMC Department No. 491, Zhongfu Rd., Linkou Dist., New Taipei City 244, Taiwan Tel: +886-2-26092133 Fax: +886-2-26099303 Website: www.audixtech.com Contact e-mail: attemc_report@audixtech.com
Accreditations	The laboratory is accredited by following organizations under ISO/IEC 17025:2017 (1) NVLAP(USA) NVLAP Lab Code 200077-0 (2) TAF(Taiwan) No. 1724
Test Facilities	FCC OET Designation Number under APEC MRA by NCC is: TW1724 ISED CAB Identifier Number under APEC TEL MRA by NCC is TW1724 (1) No.8 Shielded Room (2) No.1 3m Semi Anechoic Chamber

3.13.Measurement Uncertainty

Te	Test Items/Facilities		Frequency Range	Uncertainty
Conduction Test		landian Tark	9kHz-150kHz	±3.7dB
		luction lest	150kHz-30MHz	±3.4dB
			30MHz-200MHz, 3m, Horizontal	±3.8dB
			200MHz-1000MHz, 3m, Horizontal	±4.1dB
		N 12 C :	30MHz-200MHz, 3m, Vertical	±4.5dB
	\boxtimes	No.1 3m Semi Anechoic Chamber	200MHz-1000MHz, 3m, Vertical	±4.5dB
		7 meenote chamber	1GHz-6GHz, 3m	±4.7dB
			6GHz-18GHz, 3m	±4.1dB
			18GHz-40GHz, 3m	±3.52dB
			30MHz-200MHz, 3m, Horizontal	±3.9dB
		No.3 3m Semi Anechoic Chamber	200MHz-1000MHz, 3m, Horizontal	±4.2dB
			30MHz-200MHz, 3m, Vertical	±4.3dB
D 11			200MHz-1000MHz, 3m, Vertical	±4.5dB
Radiation Test		No.4 3m Semi Anechoic Chamber	30MHz-200MHz, 3m, Horizontal	±4.1dB
Test			200MHz-1000MHz, 3m, Horizontal	±4.5dB
			30MHz-200MHz, 3m, Vertical	±4.4dB
			200MHz-1000MHz, 3m, Vertical	±4.8dB
			1GHz-6GHz, 3m	±5.0dB
			6GHz-18GHz, 3m	±4.7dB
			30MHz-200MHz, 3m, Horizontal	±4.2dB
			200MHz-1000MHz, 3m, Horizontal	±4.3dB
		No.5 3m Semi	30MHz-200MHz, 3m, Vertical	±4.3dB
		Anechoic Chamber	200MHz-1000MHz, 3m, Vertical	±4.7dB
			1GHz-6GHz, 3m	±4.8dB
			6GHz-18GHz, 3m	±4.5dB

Remark : Uncertainty = $ku_c(y)$

Test Item	Uncertainty
20dB Bandwidth	±0.2kHz
99% Occupied Bandwidth	±0.38%
Carrier Frequency Separation	±0.2kHz
Time of Occupancy	±0.03sec
Maximum peak Output power	± 0.52dB
Conducted Emission Limitations	± 0.13dB

4. MEASUREMENT EQUIPMENTLIST

4.1. Conducted Emission Measurement

Item	Туре	Manufacturer	Model No.	Serial No.	Cal. Date	Cal. Interval
1.	Test Receiver	R&S	ESR3	101774	2022.01.11	1 Year
2.	A.M.N. R&S		ENV4200	100169	2021.11.04	1 Year
3.	L.I.S.N. Kyori		KNW-407	8-855-9	2021.12.19	1 Year
4.	Pulse Limiter	R&S	ESH3-Z2	100354	2021.12.23	1 Year
5.	Digital Thermo-Hygro Meter	iMax	HTC-1	No.8 S/R	2022.04.14	1 Year
6.	Coaxial Cable	Yeida	RG/58AU	CE-08	2021.09.13	1 Year
7.	Test Software	Audix	e3	V6.120619c	N.C.R.	N.C.R.

4.2. Radiated Emission Measurement

Item	Туре	Manufacturer	Model No.	Serial No.	Cal. Date	Cal. Interval
1.	Spectrum Analyzer	Agilent	N9010A-526	MY53400071	2021.09.09	1 Year
2.	Spectrum Analyzer	Keysight	N9010B-544	MY55460198	2022.04.08	1 Year
3.	Test Receiver	R&S	ESCS30	100039	2022.06.01	1 Year
4.	Amplifier	HP	8447D	2944A06305	2022.01.05	1 Year
5.	Microwave Amplifier	HP	8449B	3008A01284	2022.06.01	1 Year
6.	Microwave Amplifier	Keysight	83051A	MY53010042	2021.07.30	1 Year
7.	Loop Antenna	ETS LINDGREN	6512	00035867	2021.09.29	1 Year
8.	Bilog Antenna	TESEQ	CBL6112D	33821	2021.07.16	1 Year
9.	Double-Ridged Waveguide Horn	EMCO	3115	9112-3775	2022.05.18	1 Year
10.	Horn Antenna	COM-POWER	AH-840	101092	2022.01.06	1 Year
11.	2.4GHz Notch Filter	K&L Microwave	7NSL10-2441.5/E 130.5-O/O	2	2021.07.24	1 Year
12.	3GHz Notch Filter	Microwave	H3G018G1	484796	2021.07.24	1 Year
13.	Coaxial Cable	MIYAZAKI	5D2W	RE-11	2022.01.20	1 Year
14.	Coaxial Cable	HUBER+SUHNER	SUCOFLEX 106	RE-14	2022.01.20	1 Year
15.	Coaxial Cable	HUBER+SUHNER	SUCOFLEX 102	RE-30	2021.08.25	1 Year
16.	Digital Thermo-Hygro Meter	iMax	HTC-1	No.1 3m A/C	2022.04.14	1 Year
17.	Test Software	Audix	e3	V6.120619c	N.C.R.	N.C.R.

4.3. RF Conducted Measurement

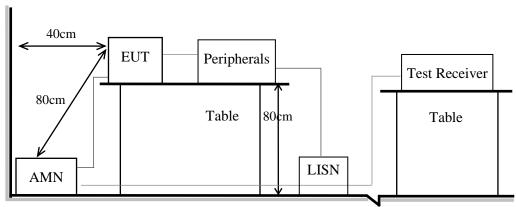
Item	Туре	Manufacturer	Model No.	Serial No.	Cal. Date	Cal. Interval
1.	Spectrum Analyzer Keysight		N9020B-544	MY57120357	2022.01.05	1 Year
2.	Digital Thermo-Hygro Meter	iMax	HTC-1	RF-03	2022.04.14	1 Year

5. CONDUCTED EMISSION

5.1. Block Diagram of Test Setup

5.1.1. Block Diagram of EUT Indicated as section 3.10

5.1.2. Shielded Room Setup Diagram



Ground Plane

5.2. Conducted Emission Limit

	-			
Eraguanay	Conducted Limit			
Frequency	Quasi-Peak Level	Average Level		
150kHz ~ 500kHz	66 ~ 56 dBμV	56 ~ 46 dBμV		
500kHz ~ 5MHz	56 dBμV	46 dBμV		
5MHz ~ 30MHz	60 dBμV	50 dBμV		

Remark1.: If the average limit is met when using a Quasi-Peak detector, the measurement using the average detector is not required.

2.: The lower limit applies to the band edges.

5.3. Test Procedure

- 5.3.1. To set up the EUT as indicated in ANSI C63.10. The EUT was placed on the table which has 80 cm height to the ground and 40 cm distance to the conducting wall.
- 5.3.2. Power supplier of the EUT was connected to the AC mains through an Artificial Mains Network (A.M.N.).
- 5.3.3. The AC power supplies to all peripheral devices must be provided through line impedance stabilization network (L.I.S.N.)
- 5.3.4. Checking frequency range from 150kHz to 30 MHz and record the emission which does not have 20 dB below limit.

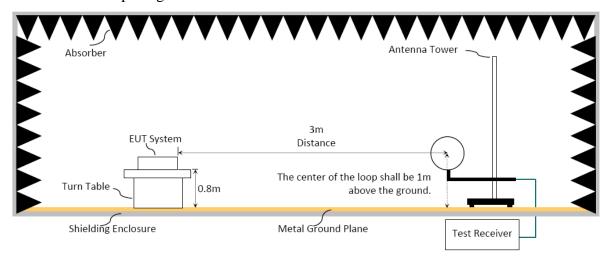
5.4. Test Results

6. RADIATED EMISSION

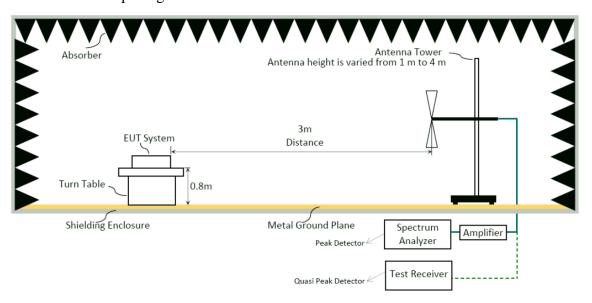
6.1. Block Diagram of Test Setup

6.1.1. Block Diagram of EUT Indicated as section 3.10

6.1.2. Setup Diagram for 9kHz-30MHz



6.1.3. Setup Diagram for 30-1000MHz

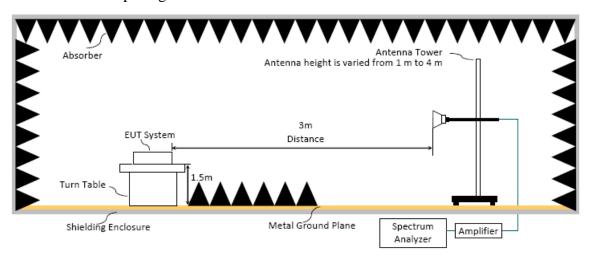


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6.1.4. Setup Diagram for above 1GHz



6.2. Radiated Emission Limits

In any 100kHz bandwidth outside the frequency band, the radio frequency power produced by the intentional radiator shall be at least 20dB below that in the 100kHz bandwidth within the band that contains the highest level. In addition, radiated emissions which fall in restricted bands, as defined in Section 15.205/RSS-Gen Section 8.10 table 6, must also comply with the radiated emission limits specified as below.

Frequency (MHz)	Distance(m)	Limits			
rrequency (wirtz)	Distance(III)	dBµV/m	$\mu V/m$		
0.009 - 0.490	300	67.6-20 log f(kHz)	2400/f kHz		
0.490 - 1.705	0.490 - 1.705 30		24000/f kHz		
1.705 - 30	30	29.5	30		
30 - 88	3	40.0	100		
88- 216	3	43.5	150		
216- 960	3	46.0	200		
Above 960	3	54.0	500		
Above 1000	3	74.0 dBμV/m (Peak)			
Above 1000		54.0 dBµV/m (Average)			

Remark : (1) $dB\mu V/m = 20 \log (\mu V/m)$

- (2) The tighter limit applies to the edge between two frequency bands.
- (3) Distance refers to the distance in meters between the measuring instrument antenna and the closed point of any part of the device or system.
- (4) Fundamental and emission fall within operation band are exempted from this section.
- (5) Pursuant to ANSI C63.10: 6.6.4.3, if the maximized peak measured value complies with the average limit, then it is unnecessary to perform an average measurement.

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6.3. Test Procedure

Frequency Range 9kHz~30MHz:

The EUT setup on the turntable which has 0.8 m height to the ground. The turn table rotated 360 degrees and antenna fixed to 1 m to find the maximum emission level. In order to find the maximum emission, all of the interface cables were manipulated according to ANSI C63.10-2013 regulation.

- (1) RBW = 9kHz with peak and average detector.
- (2) Detector: average and peak (9kHz-490kHz)

Q.P. (490kHz-30MHz)

Frequency Range 30MHz ~ 25GHz:

The EUT setup on the turn table which has 80cm (for 30-1000MHz) and 1.5m (for above 1GHz) height to the ground. The turn table rotated 360 degrees and antenna varied from 1 m to 4 m to find the maximum emission level. Both horizontal and vertical polarization are required. In order to find the maximum emission, all of the interface cables were manipulated according to ANSI C63.10-2013 regulation.

Frequency below 1GHz:

Spectrum Analyzer is used for pre-testing with following setting:

- (1)RBW = 120KHz
- (2)VBW $\geq 3 \times RBW$.
- (3)Detector = Peak.
- (4)Sweep time = auto.
- (5)Trace mode = max hold.
- (6) Allow sweeps to continue until the trace stabilizes.
- Note 1: When peak-detected value is lower than limit that the measurement using the Q.P. detector is not required, otherwise using Q.P. for final measurement.
- Note 2: When the radiated emissions limits are expressed in terms of the average value of the emissions, and pulsed operation is employed, the measurement field strength shall be determined by averaging over one complete pulse train, including blanking intervals, as long as the pulse train does not exceed 0.1 seconds.

Frequency above 1GHz to 10th harmonic(up to 25 GHz): Peak Detector:

- (1)RBW = 1MHz
- (2)VBW $\geq 3 \times RBW$.
- (3)Detector = Peak.
- (4)Sweep time = auto.
- (5)Trace mode = max hold.
- (6) Allow sweeps to continue until the trace stabilizes.

Note: When peak-detected value is lower than limit that the measurement using the average detector is not required, otherwise using average detector for final measurement.



Average Detector:

Option 1:

(1)RBW = 1MHz

(2)VBW $\geq 1/T$

Mode	TX _{on} (ms)	1/TX _{on} (kHz)	$VBW(>1/TX_{on})$ (kHz)
BT	2.890	0.346	3

- (3)Detector = Peak.
- (4)Sweep time = auto.
- (5)Trace mode = max hold.
- (6) Allow sweeps to continue until the trace stabilizes.

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Average Emission Level= Peak Emission Level+ D.C.C.F.

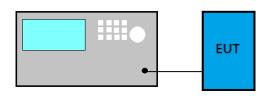
6.4. Measurement Result Explanation

- Peak Emission Level($dB\mu V/m$)=Antenna Factor(dB/m) + Cable Loss (dB)— Preamp Gain (dB)+ Reading($dB\mu V$).
- Average Emission Level($dB\mu V/m$)= Antenna Factor(dB/m) + Cable Loss (dB)-Preamp Gain (dB)+ Reading($dB\mu V$).
- □ Average Emission Level(dBμV/m)= Peak Emission Level(dBμV/m)+ DCCF(dB) Duty Cycle Correction Factor (DCCF)(dB)= $20log(TX_{on}/TX_{on+off})$ presented in section 3.7.
- \square ERP(dBm)= Peak Emission Level(dB μ V/m) -95.2dB-2.14dB

6.5. Test Results

7. 20dB/OCCUPIED BANDWIDTH

7.1. Block Diagram of Test Setup



7.2. Specification Limits

Alternatively, frequency hopping systems operating in the 2400-2483.5MHz band may have hopping channel carrier frequencies that are separated by 25kHz or two-thirds of the 20dB bandwidth of the hopping channel, whichever is greater.

7.3. Test Procedure

Following measurement procedure is reference to ANSI C63.10:2013:

For 20dB Bandwidth

- (1) Set Span range 2~5 times the OBW
- (2) Set RBW close to 1% to 5% of OBW.
- (3) Set VBW≥3xRBW.
- (4) Detector = Peak.
- (5) Trace mode = Max hold.
- (6) Sweep = Auto couple.
- (7) Allow the trace to stabilize.
- (8) Setting channel bandwidth function x dB to -20 dB to record the final bandwidth.

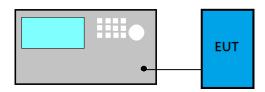
For 99% Occupied Bandwidth

- (9) Set Span range 1.5~5 times the OBW
- (10) Set RBW close to 1% to 5% of OBW.
- (11) Set VBW≥3xRBW.
- (12) Detector = Peak.
- (13) Trace mode = Max hold
- (14) Sweep = Auto couple.
- (15) Allow the trace to stabilize.

7.4. Test Results

8. CARRIER FREQUENCY SEPARATION

8.1. Block Diagram of Test Setup



8.2. Specification Limits

Alternatively, frequency hopping systems operating in the 2400-2483.5MHz band may have hopping channel carrier frequencies that are separated by 25kHz or two-thirds of the 20dB bandwidth of the hopping channel, whichever is greater, provided the systems operate with an output no greater than 125mW.

8.3. Test Procedure

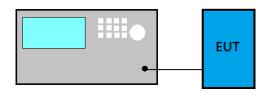
Following measurement procedure is reference to ANSI C63.10:2013:

- (1) Span = Wide enough to capture the peaks of two adjacent channels
- (2) RBW: Start with the RBW set to approximately 30% of the channel spacing; adjust as necessary to best identify the center of each individual channel.
- (3) $VBW \ge RBW$
- (4) Sweep = Auto
- (5) Detector function = Peak
- (6) Trace = Max hold
- (7) Allow the trace to stabilize.

8.4. Test Results

9. TIME OF OCCUPANCY

9.1. Block Diagram of Test Setup



9.2. Specification Limits

Frequency hopping systems in the 2400-2483.5MHz shall use at least 15 non-overlapping channels. The average time of occupancy on any channel shall not be greater than 0.4 seconds within a period of 0.4 seconds multiplied by number of hopping channels employed.

9.3. Test Procedure

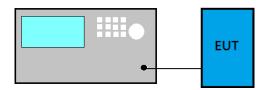
Following measurement procedure is reference to ANSI C63.10:2013:

- (1) Span: Zero span, centered on a hopping channel.
- (2) RBW shall be \leq channel spacing and where possible RBW should be set >> 1/T, where T is the expected dwell time per channel.
- (3) Sweep: As necessary to capture the entire dwell time per hopping channel; where possible use a video trigger and trigger delay so that the transmitted signal starts a little to the right of the start of the plot. The trigger level might need slight adjustment to prevent triggering when the system hops on an adjacent channel; a second plot might be needed with a longer sweep time to show two successive hops on a channel.
- (4) Detector function = Peak
- (5) Trace = Max hold

9.4. Test Results

10. NUMBER OF HOPPING CHANNELS

10.1.Block Diagram of Test Setup



10.2. Specification Limits

Frequency hopping systems which use fewer than 20 hopping frequencies may employ intelligent hopping techniques to avoid interference to other transmissions. Frequency hopping systems may avoid or suppress transmissions on a particular hopping frequency provided that a minimum of 15 non-overlapping channels.

10.3.Test Procedure

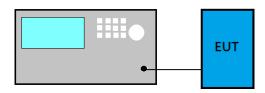
Following measurement procedure is reference to ANSI C63.10:2013:

- (1) Span: The frequency band of operation. Depending on the number of channels the device supports, it may be necessary to divide the frequency range of operation across multiple spans, to allow the individual channels to be clearly seen.
- (2) RBW: To identify clearly the individual channels, set the RBW to less than 30% of the channel spacing or the 20 dB bandwidth, whichever is smaller.
- (3) $VBW \ge RBW$
- (4) Sweep = Auto
- (5) Detector function = Peak
- (6) Trace = m=Max hold
- (7) Allow the trace to stabilize.

10.4.Test Results

11.MAXIMUM PEAK OUTPUT POWER

11.1.Block Diagram of Test Setup



11.2. Specification Limits

The Limits of maximum Peak Output Power for frequency hopping systems in 2400-2483.5MHz is: 0.125Watt. (21dBm)

11.3.Test Procedure

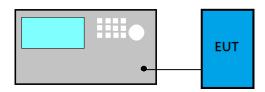
Following measurement procedure is reference to ANSI C63.10:2013:

- (a) Use the following spectrum analyzer settings
 - (1) Span: Approximately five times the 20 dB bandwidth, centered on a hopping channel.
 - (2) RBW > 20 dB bandwidth of the emission being measured.
 - (3) $VBW \ge RBW$
 - (4) Sweep: Auto
 - (5) Detector function: Peak
 - (6) Trace: Max hold
- (b) Allow trace to stabilize.
- (c) Use the marker-to-peak function to set the marker to the peak of the emission.

11.4.Test Results

12.EMISSION LIMITATIONS

12.1.Block Diagram of Test Setup



12.2. Specification Limits

In any 100kHz bandwidth outside the frequency band in which the spread spectrum or digitally modulated intentional radiator is operating, the radio frequency power that is produced by the intentional radiator shall be at least 20dB below that in the 100kHz bandwidth within the band that contains the highest level of the desired power, based on either an RF conducted or a radiated measurement. If the transmitter complies with the conducted power limits based on the use of RMS averaging over a time interval, that the required attenuation shall be 30 dB instead of 20 dB.

Attenuation below the general limits specified in Section 15.209(a)/RSS-Gen Section 8.9table 4is not required. In addition, radiated emissions which fall in restricted bands, as defined in Section 15.205(a)/RSS-Gen Section 8.10 table 6,, must also comply with the radiated emission limits specified in Section 15.209(a)/RSS-Gen Section 8.9 table 4 (See Section 15.205(c)).

12.3.Test Procedure

Following measurement procedure is reference to ANSI C63.10:2013:

- (1) Set span wide enough to capture the peak level of the in-band emission and all spurious emissions; up to 10th harmonic.
- (2) RBW = 100 kHz
- (3) $VBW \ge RBW$
- (4) Sweep = Auto
- (5) Detector function = Peak
- (6) Trace = Max hold

12.4.Test Results





13.DEVIATION TO TEST SPECIFICATIONS

[NONE]



APPDNDIX A

TEST DATA AND PLOTS

(Model: 16ZB90Q)



APPDNDIX B

TEST PHOTOGRAPHS

(Model: 16ZB90Q)